



DRIP XVIII

18th CONFERENCE ON
DEFECTS-RECOGNITION,
IMAGING AND PHYSICS
IN SEMICONDUCTORS

08-12 SEPTEMBER, 2019
BERLIN, GERMANY



organized by

FBH
Ferdinand-Braun-Institut
Leibniz-Institut für
Höchstfrequenztechnik

and

IKZ
Leibniz Institute
for Crystal Growth



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Materials

- Wide band-gap materials (SiC, group III-nitrides, ZnO)
- Group IV semiconductors (Si, Ge, diamond, etc.)
- III-V compound semiconductors (GaAs, InP, ternary and diluted magnetic materials)
- Materials for oxide electronics
- Photovoltaic materials
- Nanomaterials
- Novel device structures
- Novel 2D semiconductors

Topics

- Recognition, Imaging and Physics of point and extended defects in semiconductors
- Diagnostics techniques of crystal growth and processing of semiconductor materials
- Device imaging and mapping for performance and reliability evaluation
- Defect and degradation analysis in optoelectronic and electronic devices
- Imaging techniques and instruments (scanning microscopies, X-ray, electron beam, noncontact electrical, optical and thermal imaging techniques)
- New frontiers of atomic-scale defect assessment (STM, AFM, SNOM, TEM, etc.)
- Multi-dimensional characterization with nano-scale space resolution (spectroscopic, X-ray, etc.)

Conference Chairs

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